



# SID4-HR

## WAVE FRONT SENSOR



### ↓ SPECIFICATIONS

|                                |                                      |
|--------------------------------|--------------------------------------|
| Wavelength Range               | 400 - 1100 nm                        |
| Aperture Dimension             | 8.9 x 11.8 mm <sup>2</sup>           |
| Spatial Resolution             | 29.6 μm                              |
| Phase and Intensity Sampling   | 300 x 400 (>120 000 points)          |
| Resolution (Phase)             | < 2 nm RMS                           |
| Accuracy                       | 15 nm RMS                            |
| Dynamic range                  | > 500 μm                             |
| Radius of Curvature range (*)  | 4 mm to + ∞ (*)                      |
| Curvature resolution           | < 5.10 <sup>-4</sup> m <sup>-1</sup> |
| Maximum Numerical aperture (*) | 0.5 (*)                              |
| Acquisition Rate               | > 30 fps                             |
| Real-time processing frequency | 3 fps (full resolution)              |
| Dimensions (WxHxL)             | 54 x 46 x 79 mm                      |
| Weight                         | ~250 g                               |

(\*) optional software necessary

### → SID4-High Resolution

wave front sensor is adapted for optical metrology needs. It associates the SID4 ease of implementation with ultra high resolution. The SID4-HR gives an instantaneous measurement on the whole object to characterize.

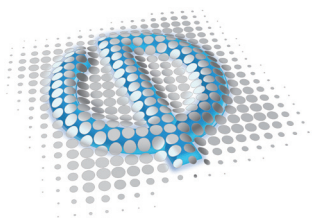
It is optimized to **surface inspection** (roughness, high frequency defects...) and **optical components characterization** (lens, objective, aspheric...).

The high performance camera increases the precision for laser characterization.

The 300 x 400 phase map sampling with such compactness make the SID4-HR a unique tool for optics and laser in research and industry.

### → KEY FEATURES

- Very high resolution (400 x 300)
- Large analysis pupil (8,9 mm x 11,8 mm)
- High dynamic range
- Instantaneous measurement on a large field
- Optimal signal to noise ratio
- Compactness for easy implementation



**海纳光学**

电话：0755-84870203

邮箱：[sales@highlightoptics.com](mailto:sales@highlightoptics.com)